


Based on Form PTO-1449 (3/90) LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary) 	ATTY. DOCKET NO. 456110-2360	SERIAL NO. 10/561,729
	APPLICANT Philip KLIPSTEIN	
	FILING DATE February 12, 2007	GROUP 2811

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA 2007/0034898	02/15/07	Tennant, William E. et al.			
	AB 4 679 063	07/17/87	White Anthony M.			
	AC					
	AD					
	AE					

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AF	WO 2005 004243	01/13/05	PCT				
AG							
AH							
AI							
AJ							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

AK	S. MAIMON et al: "nBn detector, an infrared detector with reduced dark current and higher operating temperature", Applied Physics Letters, AIP, Amer. Inst. of Physics, Melville, NY, vol.89, no.15, 10 Oct 2006, XP012086238
AL	Shyh WANG, chapter 8 of his book entitled "Fundamentals of Semiconductor Theory and Device Physics" (published by Prentice Hall, ISBN 0-13-344425-2)
AM	J BAJAJ, "State-of-the-art HgCdTe Infrared Devices" SPIE proceedings no. 3948, pages 42-54, San Jose, January 2000 (Fig. 3)
AN	P C KLIPSTEIN et al., "Antimonide Based Materials for Infrared Detection" SPIE proceedings number 4820, pages 653-662, Seattle, July 2002
AO	P C KLIPSTEIN et al., "Semiconductor Heterospitaxy", published by World Scientific, Singapore, pages 515-523, ISBN 981 02 2479 6
AP	T ASHLEY et al., in "Large Format MWIR Focal Plane Arrays", in SPIE proceedings vol. 4820, pages 400-405
AQ	"Growth and Characterization of Semiconductors", edited by R A Stradling and P C Klipstein, published by Adam Hilger (1990), ISBN 0-85274-131-6

EXAMINER /John Ingham/	DATE CONSIDERED 03/26/2009
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.